

<b>Notice of References Cited</b>	Application/Control No. 09/867,967	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
	Examiner Nhon T Diep	Art Unit 2613	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,763,070	07-2004	Lee, Yuen-Wen	375/240.2
	B	US-6,665,346	12-2003	Lee et al.	375/240.29
	C	US-6,263,021	07-2001	Sethuraman et al.	375/240.03
	D	US-6,771,703	08-2004	Oguz et al.	375/240.03
	E	US-6,671,322	12-2003	Vetro et al.	375/240.16
	F	US-6,535,556	03-2003	Kato et al.	375/240.05
	G	US-6,442,207	08-2002	Nishikawa et al.	375/240.26
	H	US-6,763,067	07-2004	Hurst, Robert N.	375/240.03
	I	US-60238979	10-2000	Hurst	374/240.03
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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